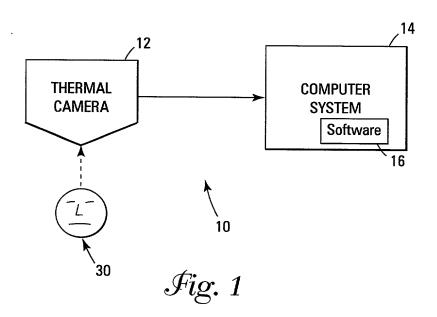
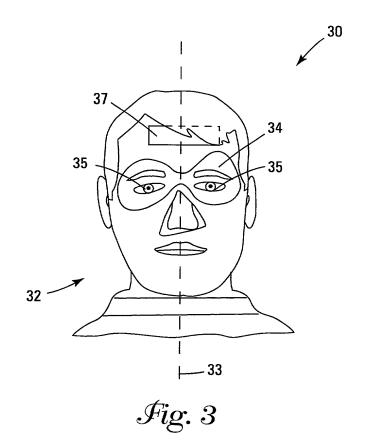
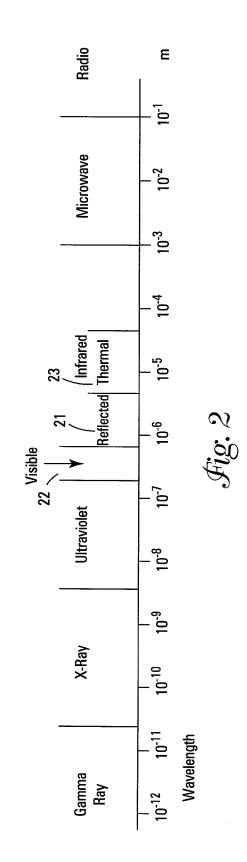
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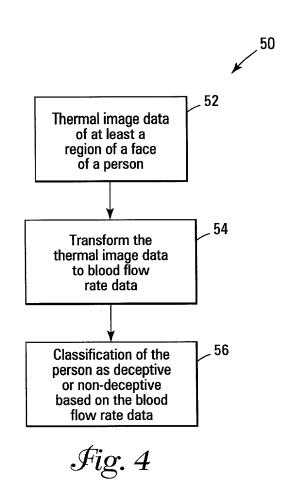




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Fig. 5A



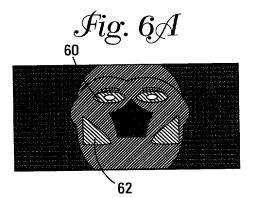
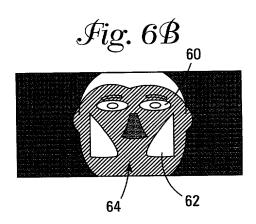
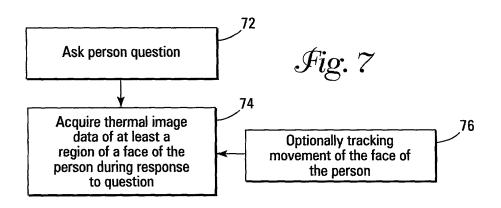


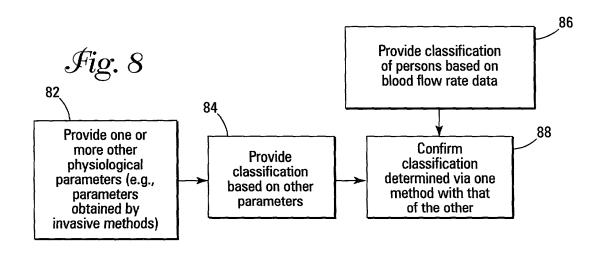
Fig. 5B

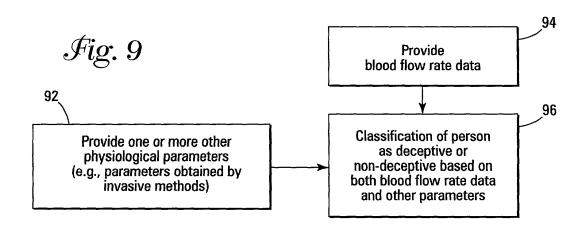




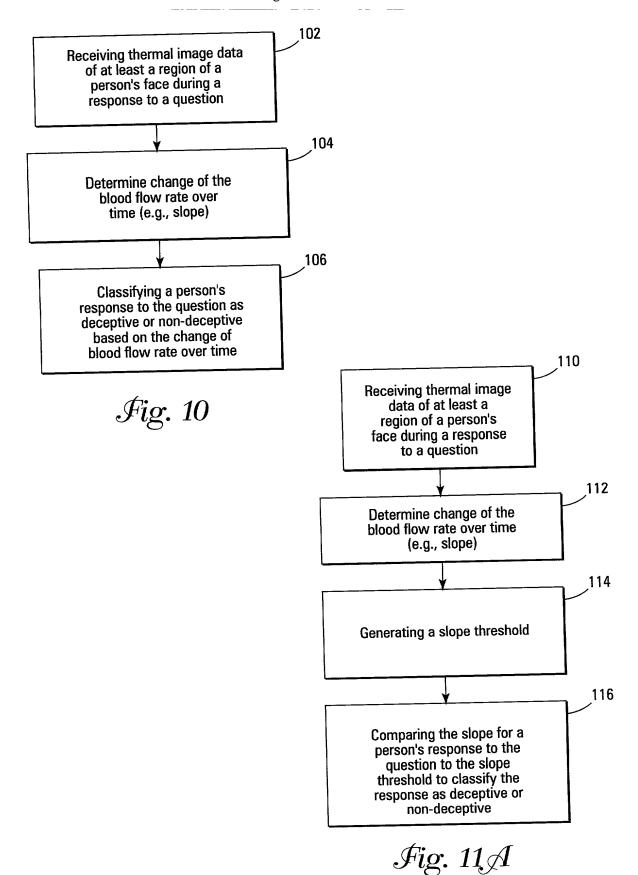
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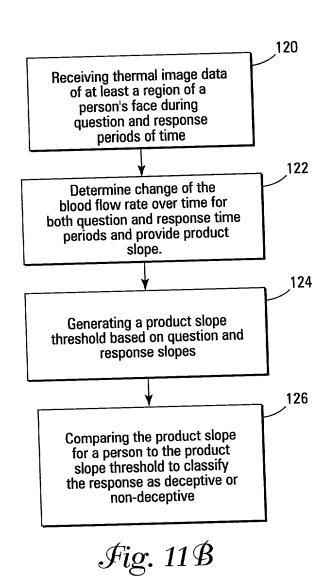




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